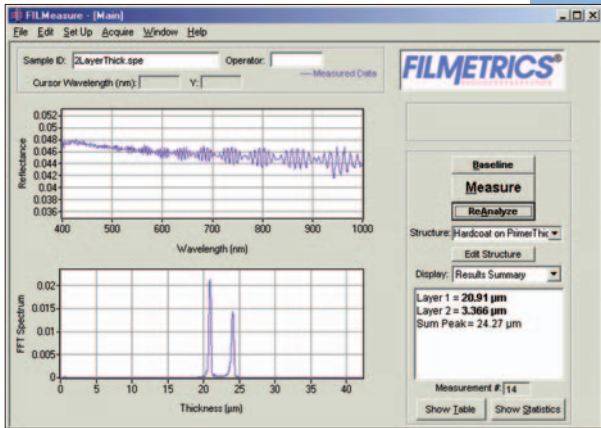
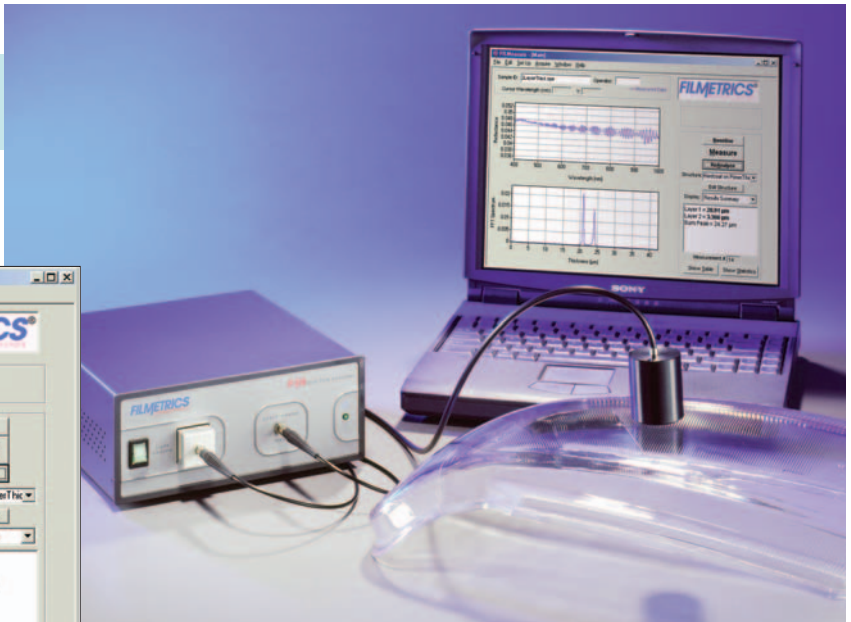


F20-HC



An Advanced Thin-Film Measurement System at an Affordable Price

APPLICATIONS

**Thick films in
hardcoat and
ophthalmic
applications**

The F20-HC is based on the Filmetrics F20 platform where analysis of spectral reflectance data provides film measurement results quickly. Plus, the advanced simulation algorithms in the F20-HC software is specifically designed to measure single and multiple layers (e.g., primer/hardcoat) encountered in thick film applications.

For applications where the surface is curved, the CP-1 Contact Probe may be used.

SPECIFICATIONS:

Thickness range:	0.1 to 50 microns
Spot Size:	200 µm to 1 cm
Sample Size:	From 1 mm to 300 mm diameter and up
Accuracy*:	The greater of 0.4% or 10 Å
Precision*:	0.001 µm
Stability*:	0.001 µm
Spectrometer Type:	512-element silicon array
Light Source:	Regulated Tungsten-Halogen
Power Requirements:	100-240 VAC, 50-60 Hz, 0.3-0.1 A

* Typical values in spectrum matching mode. Layer stack dependent.



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